## In the Claims:

(Currently Amended) A set of integrated capacitor arrangements (10),

having at least two integrated capacitor arrangements-(10), which have been produced in accordance with identical geometrical designs and which each contain a circuitry-effective main capacitor-(12) and at least one correction capacitor-(16),

having an electrically conductive <u>antifuse</u> connection between the correction capacitor and the main capacitor in <u>one-a first of the</u> capacitor arrangements, the connection having been produced after the production of the main capacitor of <u>this-the first</u> capacitor arrangement,

and-having an electrically insulating <u>antifuse</u> interruption-(62) between the <u>same</u>-correction capacitor-(16) of the first capacitor arrangement and the main capacitor-(12) in the other a second of the capacitor arrangements (10), the interruption having been produced in accordance with the geometrical designs,

<u>having at least one further correction capacitor in each capacitor arrangement,</u>

having a further electrically conductive fuse connection between the further correction capacitor and the main capacitor in the first capacitor arrangement, the further connection having been produced in accordance with the geometrical designs, and

having a further electrically insulating fuse interruption between the further correction capacitor in the first capacitor arrangement and the main capacitor in the second capacitor arrangement, the interruption having been produced after production of the main capacitor of the second capacitor arrangement.

2. (Currently Amended) The capacitor arrangements (10) as claimed in claim 1, wherein the connection and the interruption are situated at identical positions in the capacitor arrangements (10).

- 3. (Currently Amended) The capacitor arrangements-(10) as claimed in claim 1-or-2, wherein at least one of: the connection has been produced by local heating, and/or wherein the connection contains a material warpage which penetrates through a dielectric-and arose on account of the heating.
- 4. (Currently Amended) The capacitor arrangements-(10) as claimed in claim 1 one of the preceding claims, wherein at least one of: a material covering the connection contains a cutout leading to the connection, wherein a material covering the interruption-(62) contains a cutout-(58) leading to the interruption, and/or wherein the cutouts are filled with a passivating material.
  - 5. (Cancelled)
- 6. (Currently Amended) The capacitor arrangements (10) as claimed in claim 51, wherein the further interruption arose as a result of local heating and vaporization of an electrically conducting section.
- 7. (Currently Amended) The capacitor arrangements-(110) as claimed in claim 1 one of the preceding claims, wherein dielectrics of the capacitors-(112 to 116) have a thickness which is equal to the a thickness of a dielectric between metallization layers in which connection sections of connections to integrated semiconductor components are situated.
- 8. (Currently Amended) The capacitor arrangements (110) as claimed in claim 1 one of the preceding claims, wherein at least one of: the capacitors (112 to 116) have electrodes situated in more than two metallization layers, and/or wherein the electrodes are formed in a whole-area or grid-like manner.
- 9. (Currently Amended) The capacitor arrangements (10) as claimed in claim 1 one of the preceding claims, wherein dielectrics of the capacitors (12 to 16) have a thickness which is less than the a thickness of the a dielectric between metallization layers in which connection sections of

connections to integrated semiconductor components are situated, preferably less at least by half.

10. (Currently Amended) The capacitor arrangements (10, 110) as claimed in claim 1 one of the preceding claims, wherein the a capacitance of a one of the correction capacitors (14, 16; 114, 116) amounts to less than 1/3, less than 1/10, less than 1/100 or less than 1/1000 of the a capacitance of the main capacitor to which the correction capacitor is connected (12, 112).

## 11-14. (Cancelled)

15. (New) A method for producing a set of integrated grid capacitors, the method comprising:

forming at least two integrated grid capacitors in accordance with identical geometrical designs, each grid capacitor containing a plurality of transverse electrodes forming a circuitry-effective main part of the grid capacitor,

forming at least two correction transverse electrodes arranged at identical positions in the grid capacitors to have circuitry-effective lengths of different magnitudes after the production of the main part, the circuitry-effective length of each correction transverse electrode that has been changed having been lengthened by production of an electrically conductive connection or having been shortened by at least one of an electrically insulating interruption and by vaporization of part of the correction transverse electrode, and, in a material covering the shortened correction transverse electrode, forming at least one cutout leading at least one of: to the shortened correction transverse electrode and to a region at which the shortened correction transverse electrode was arranged prior to the vaporization.

- 16. (New) The method as claimed in claim 15, wherein the cutout is filled with a passivating material.
- 17. (New) The method as claimed in claim 16, wherein a plurality of cutouts lead to a correction transverse electrode, or wherein one cutout which essentially covers the entire region of the original correction transverse electrode leads to a correction transverse electrode.